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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Archer Lawrence, Jack Little, Brian Kleen, Robert Barr

Assignee: Dell Products L.P.

Title: Method and System for Test Data Capture and Compression for Electronic Device Analysis

Serial No.: 10/600,626 Filing Date: June 20, 2003

Examiner: Demetrius R. Pretlow Group Art Unit: 2863

Docket No.: KIN03003 Customer No.: 33438

Austin, Texas
March 14, 2005COMMISSIONER FOR PATENTS
PO BOX 1450
ALEXANDRIA, VA 22313-1450**RESPONSE TO NON-FINAL OFFICE ACTION**

Dear Sir:

This paper is responsive to the Office action dated March 2, 2005, having a shortened statutory period expiring June 2, 2005. Further examination and reconsideration are respectfully requested in view of the amendments and remarks set forth below.

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